



Mr. Jungho Lee

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Jungho Lee is Senior Manager of Field Process at Lam Research Korea, where has led ALD/CVD metallization process development for memory products in Samsung Global Account since 2017. He was rewarded as succeeding in applying low fluorine tungsten barrier metal or Molybdenum for word line metallization.

Prior to joining Lam, he was a Senior Engineer at Samsung Electronics, where he worked for BEOL metallization and defect engineering in 10nm and 14nm BEOL development team

Mr. Lee received a Master of Material Engineering degree from Hanyang University and Best Paper Award in KISM2022 as posting non-fluorinated tungsten paper.